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IOL and Power Cycling test systems

High measurement quality at high throughput and low total cost of test

NI IOL & Power Cycling test systems increase measurement quality and throughput and reduce testing costs on an open platform. The focus is on seamless monitoring and precise determination of all parameters of each DUT.

In addition, the systems are equipped for the special requirements of wide-bandgap technology and compatible for SiC and GaN power semiconductors. The IOL test system is MIL-STD-750D compliant.

Experience streamlined testing with our fully automated process, complete with comprehensive characterization. Benefit from high throughput facilitated by active cooling, ensuring efficient operations. Capture every single pulse of each DUT with full recording capabilities. Our versatile system offers multiple drawers compatible with standard housings, along with custom adaptations for diverse substrates. Achieve precision timing thanks to advanced FPGA technology, ensuring accurate and reliable results.



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Technical Specifications

	IOL Bench Top	IOL 80	Power Cycling
Devices under test per system (fully monitored)	16 max	80 max	2x6 stress test channel
Load current	0 up to 150A	0 up to 150A	1050A peak, 800A continuous
Measurement current	-50 up to +50mA	-50 up to +50mA	-300mA to + 300mA
Active cooling	✓	✓	active cooling, up to 2x3 separate circuits
Cooling medium	Air	Air	Liquid cooling, up to 150°C (more on request)
Monitoring parameter Case Temperature, Load Current, Load Voltage, Forward Voltage, Thermal resistance, Virtual junction temperature	✓	✓	✓
Graphical user interface (GUI) with live data	✓	✓	✓
Slide in drawers, each up to 8 DUT	1 up to 2 drawers	1 up to 10 drawers	not applicable
Dimensions in cm (width x depth x height)	60 x 80 x 96	60 x 80 x 212	163 x 120 x 215



Get more information about IOL and Power Cycling test systems by scanning the QR code or write us an e-mail to set-info@ni.com!